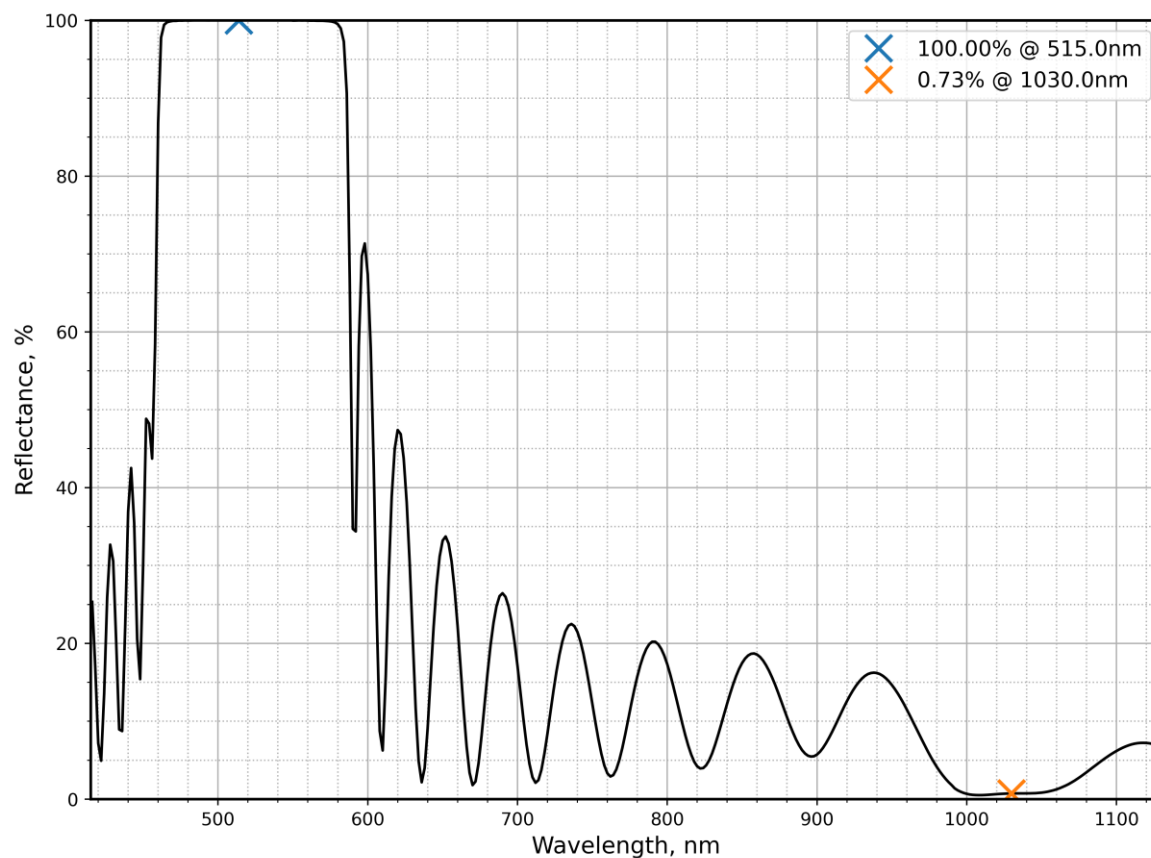


S1: (arrow mark) HRsp>99.5% @ 515 nm + Rs<5% @ 1030 nm, AOI=45°
S2: ARsp<0.6% @ 1030 nm, AOI=45 deg



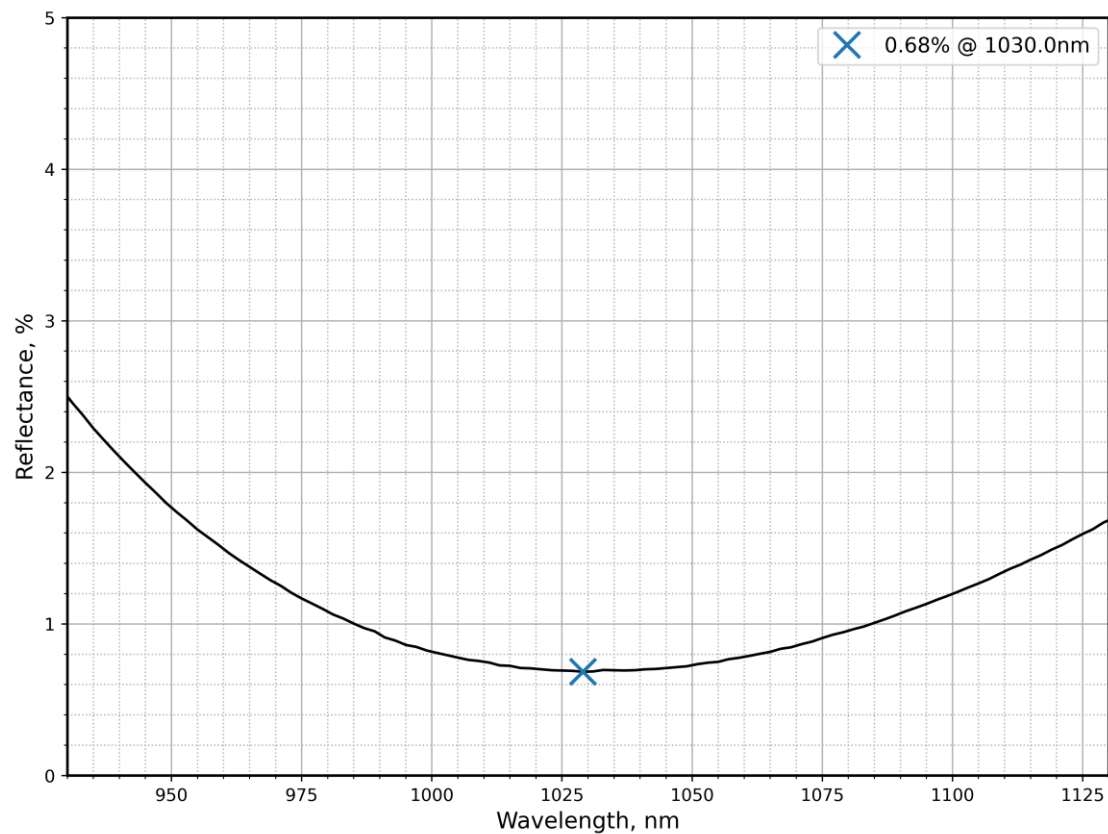
PO11330 Rs i45

Fig. 1.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.1%

S1: (arrow mark) HRsp>99.5% @ 515 nm + Rs<5% @ 1030 nm, AOI=45°
S2: ARsp<0.6% @ 1030 nm, AOI=45 deg



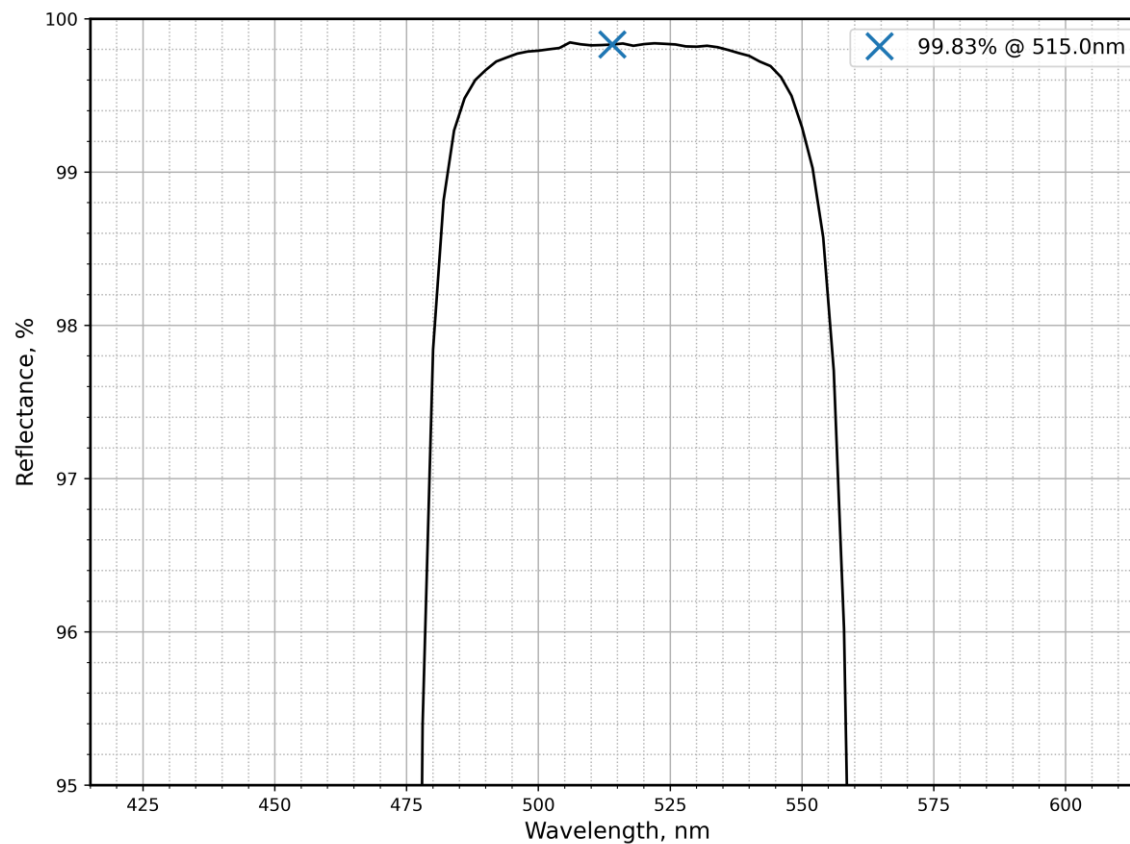
PO11330 Rs i45

Fig. 2.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.1%

S1: (arrow mark) HRsp>99.5% @ 515 nm + Rs<5% @ 1030 nm, AOI=45°
S2: ARsp<0.6% @ 1030 nm, AOI=45 deg



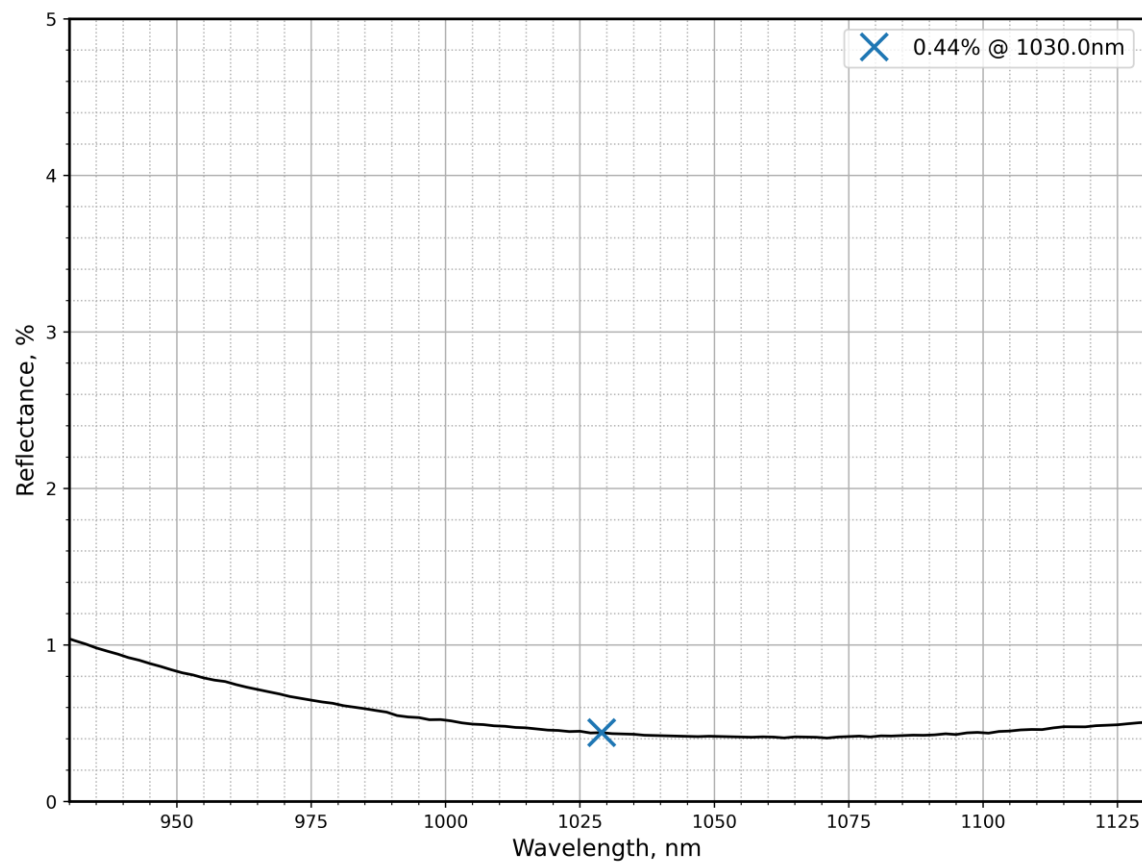
PO11330 Rp i45

Fig. 3.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.1%

S1: (arrow mark) HRsp>99.5% @ 515 nm + Rs<5% @ 1030 nm, AOI=45°
S2: ARsp<0.6% @ 1030 nm, AOI=45 deg



PO11330 Rp i45

Fig. 4.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.1%